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8/13/02

Applicant(s): Shing Lee, Haiming Wang, Adam E. Norton, Mehrdad Nikoonahad
Assignee: KLA-Tencor Corporation
Title: SYSTEM FOR MEASURING POLARIMETRIC SPECTRUM AND OTHER PROPERTIES OF A SAMPLE
Serial No.: 09/778,245 Filing Date: February 6, 2001
Examiner: Hoa Q. Pham Group Art Unit: 2877
Docket No.: M-10685-1C US

San Francisco, California
July 29, 2002

BOX Fee Amendment
COMMISSIONER FOR PATENTS
Washington, DC 20231

AMENDMENT

Dear Sir:

This responds to the Office Action mailed on January 28, 2002, setting a period for response expiring on April 28, 2002. Attached is a request for extension of time to extend the response period to July 29, 2002, July 28, 2002 being a Sunday.

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TECHNOLOGY CENTER 2800

08/13/2002 ATTORNEY (00000002 100786 09778245
01 FC:102 251.00 CH

Please amend the above-referenced application as follows:

IN THE CLAIMS:

Please cancel claims 1-88 and add new claims 89-337 as follows:

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01 FC:103 2891.00 CH
02 FC:102 751.00 CH

89. A method for measuring optically detectable properties of a sample, comprising:
focusing a polarized sample beam of broadband radiation onto the sample, said beam
having a multitude of polarization states;
collecting radiation modified by the sample by means of an objective; and

23

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